



PATENT
1152-0263P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Hideaki SAKAGUCHI Conf.: 4601
Appl. No.: 09/624,014 Group: 2857
Filed: July 21, 2000 Examiner: Mary C. BARAN
For: TESTING DEVICE & TESTING METHOD FOR
SEMICONDUCTOR INTEGRATED CIRCUITS

REPLY TO EX PARTE QUAYLE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

January 20, 2004
Tuesday After a Holiday

Sir:

In reply to the Ex parte Quayle Office Action dated November 18, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

This reply includes Remarks.

RECEIVED
JAN 23 2004
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